

**SUPSI**

# The Effect of Partial Shading on the Reliability of BC Modules

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1 – SUPSI-PVLab - University of Applied Sciences and Arts of Southern Switzerland, Mendrisio, Switzerland

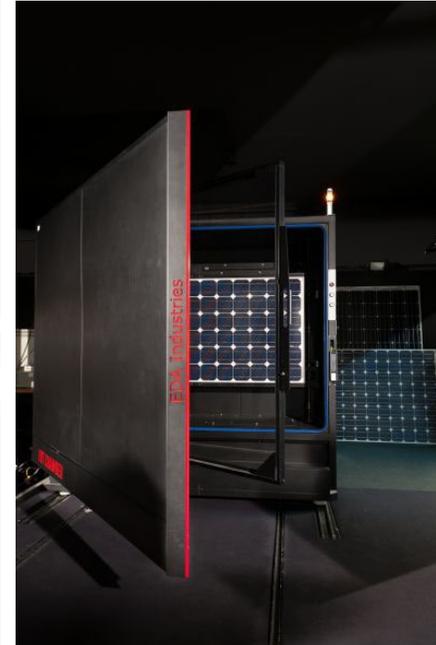
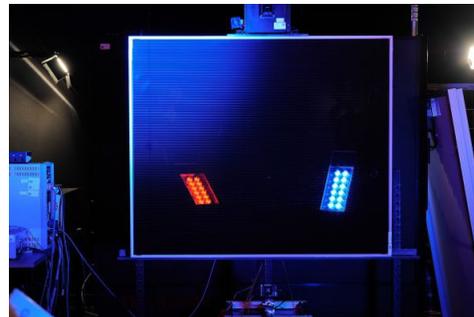
2 – CSEM PV-Center, Neuchâtel, Switzerland

3 – EPFL - École Polytechnique Fédérale de Lausanne, Institute of Electrical and Micro Engineering (IEM), Photovoltaics and Thin-Film Electronics Laboratory, Neuchâtel, Switzerland

12<sup>th</sup> BC Workshop, 4-5 December 2024  
Delft, the Netherlands

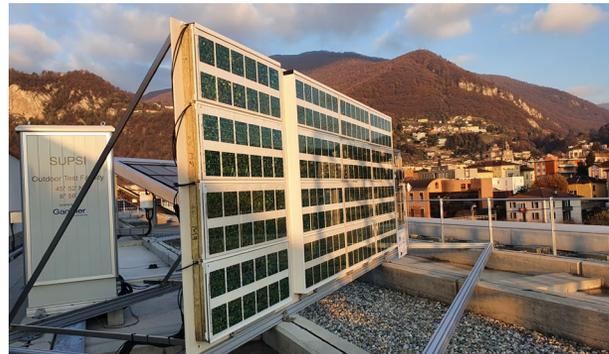
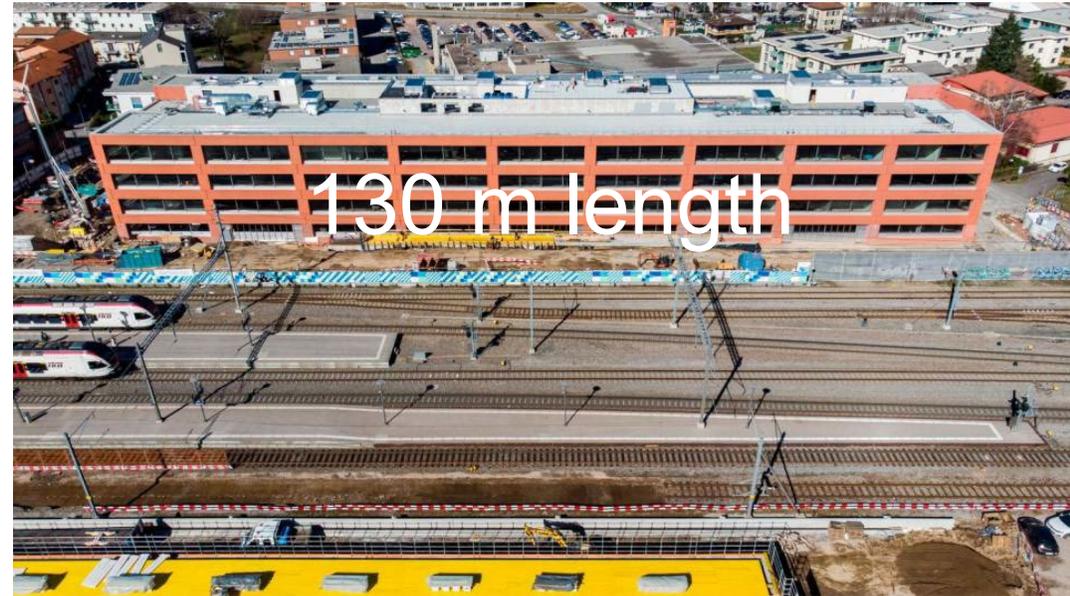
## SUPSI PVLab – Indoor

- N.2 **Pasan Flasher**, class AAA, for the electrical characterisation with best uncertainty of **+/-1.1%** (spectral response measurement at module level, spectrum fine tuning with LEDs)
- N.3 **continuous light simulators, with visible light (2) and UV light (1)**, for characterisation, stabilisation and accelerated degradation of materials
- N.2 **climate chambers**, 3 m<sup>3</sup> volume, for environmental testing with humidity and thermal cycling.
- PID testing
- N.1 **mechanical load test setup** up to **18.000 Pa** in pressure, with optional inclination up to 30°
- N.1 **hail test setup**, with max diameter of hailstone of **90 mm (accredited)**
- N.1 **mechanical test machine** for shear, pull test, 4 point bending test on materials and components (JB, connectors, laminates)
- N.1 megaohmmeter for dry and wet insulation test
- Bypass diode thermal and reverse breakdown testing.
- N.2 IR camera systems for electroluminescence and thermal mapping



## SUPSI PVLab – Outdoor

- **Outdoor monitoring area** for the energy yield evaluation and comparison to other reference technologies
- **Meteo station**, with calibrated spectroradiometers, pyranometers and reference cells for a precise monitoring of composition and quantity of light, further to environmental parameters
- N.2 IV curve tracers for string performance measurements on the field (calibration with reference modules for uncertainty reduction)
- N.1 PV system performance checker
- N.1 Insulation, short circuit current and open circuit voltage tester for PV system analysis



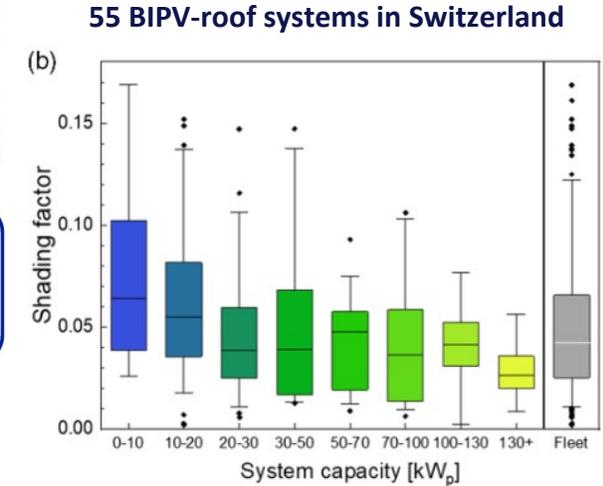
# Introduction



D. Chianese et al., EUPVSEC (2020)

$$\text{Shading factor} = \frac{\text{Time in shading fault}}{\text{Time in operation}}$$

A. Fairbrother et al. Solar RRL (2021)



## Hot spot endurance test (IEC 61215-2:2021)

- To assess module's ability to resist local-point/cell heating under partial shading
- **IEC TS 63126:2020** Guidelines for qualifying PV modules, components and materials for operation at high temperatures → **T<sub>98</sub> (175.2hour/year)**

Module Temperature	IEC 61215:2021 (T <sub>98</sub> ≤ 70°C)	Level 1 (70°C < T <sub>98</sub> ≤ 80°C)	Level 2 (80°C < T <sub>98</sub> ≤ 90°C)
<b>IEC TS 63126:2020</b>	<b>55±15°C (50±10°C*)</b>	<b>60±10°C</b>	<b>70±10°C</b>

\*IEC 61215:2016

## Objectives

- Effect of **cell technology** and **string length** on hot-spot temperature
- Sufficiency of **Hot-spot Endurance (HS) test for BIPV** in terms of testing temperature

Parallel strings («Butterfly»)

10 cells

20 cells

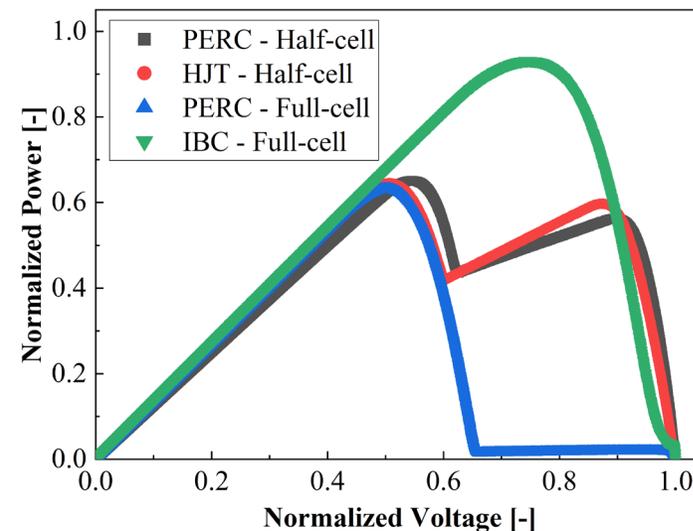
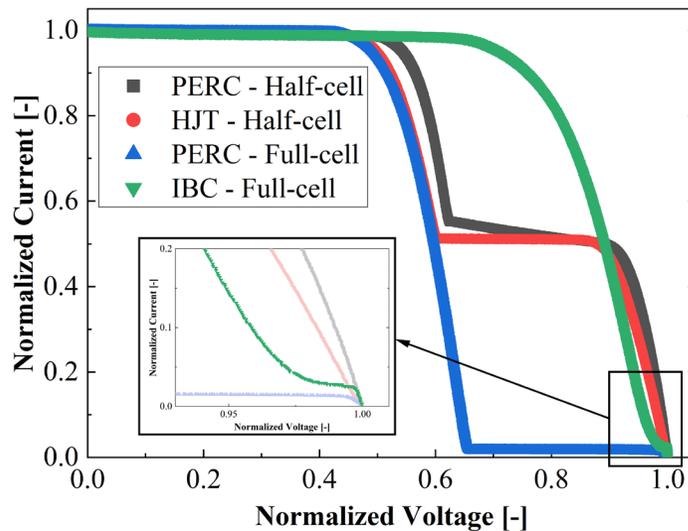
Module Technology	Indoor Hot-spot Endurance Tests	
	IEC 61215-2:2021 (55°C, 5 hours)	IEC TS 63126:2020 Level-2 (75°C, 5 hours)
1 - PERC Half-Cell (20 cells/diode)	1	1
2 - HJT Half-Cell (20 cells/diode)	1	1
3 - IBC Full-Cell (104 cells, 3 diodes)		
4 - PERC Full-cell (Short + Long (10 cells/diode + 20 cells/diode)		

IBC Full-cell PERC Half-cell HJT Half-cell PERC Full-cell

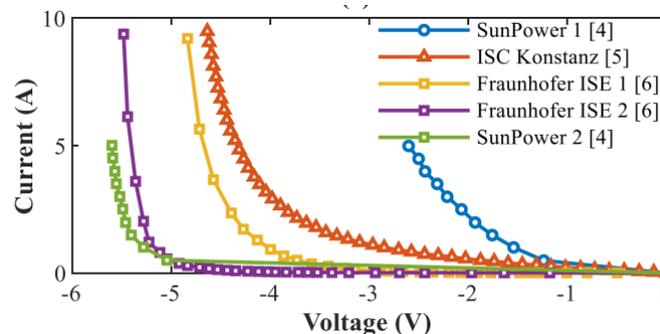
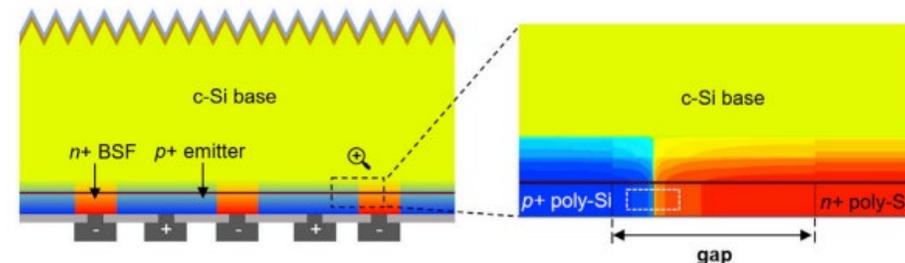
Shadow masks

Shadow mask

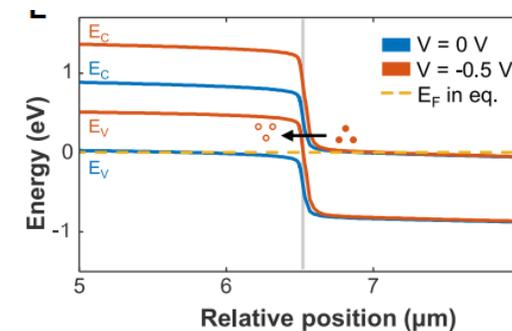
# Normalized IV & PV Curves – One Cell Shaded (100%)



- Half-cell modules → two parallel strings connected in parallel to a diode
- IBC cell → p+ and n+ junction → forms a Zener diode
  - Functions as a built-in bypass diode (tunneling)
  - Less negative breakdown voltage ( $V_{br} > -6$  V)
- Breakdown voltage of PERC at around -20 V



A. Calcabrini et al. IEEE PVSC (2021)

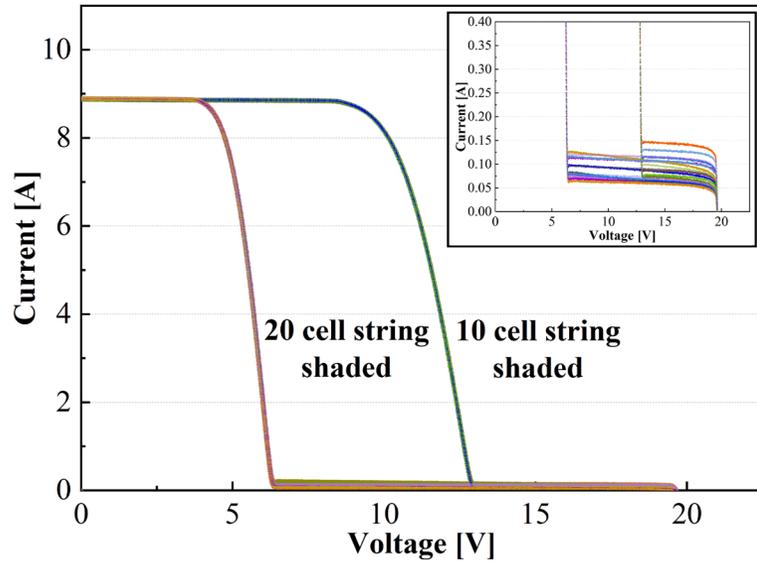


A. Calcabrini et al. CellPress (2022)

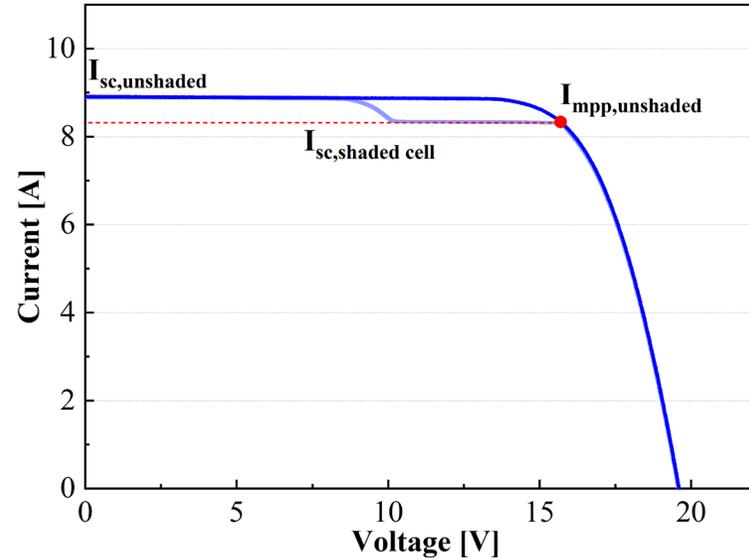
# Indoor Hot-Spot Endurance Tests

# Hot-spot Endurance test (IEC 61215-2:2021)

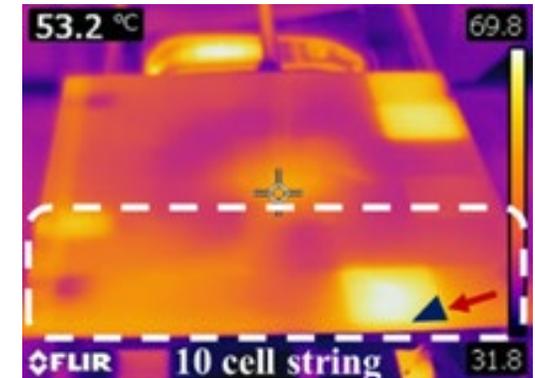
**Step 1: Cell Selection (4 cells)  
(Low and High Shunt Resistance)**



**Step 2: Worst-case shadow  
(Max Heat Dissipation)**

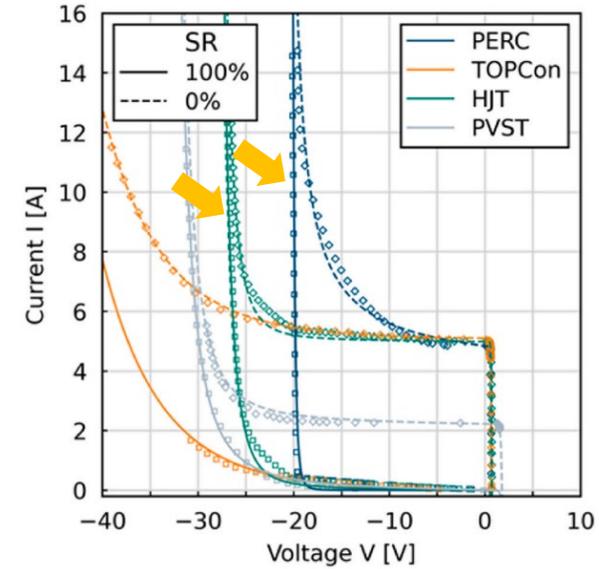
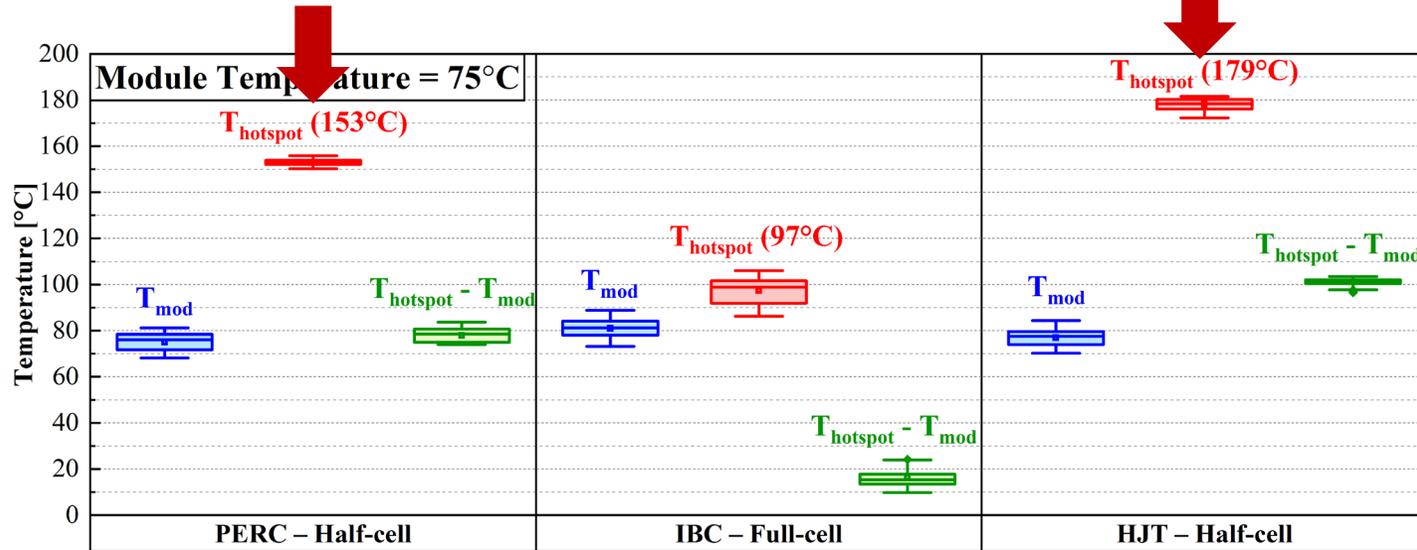
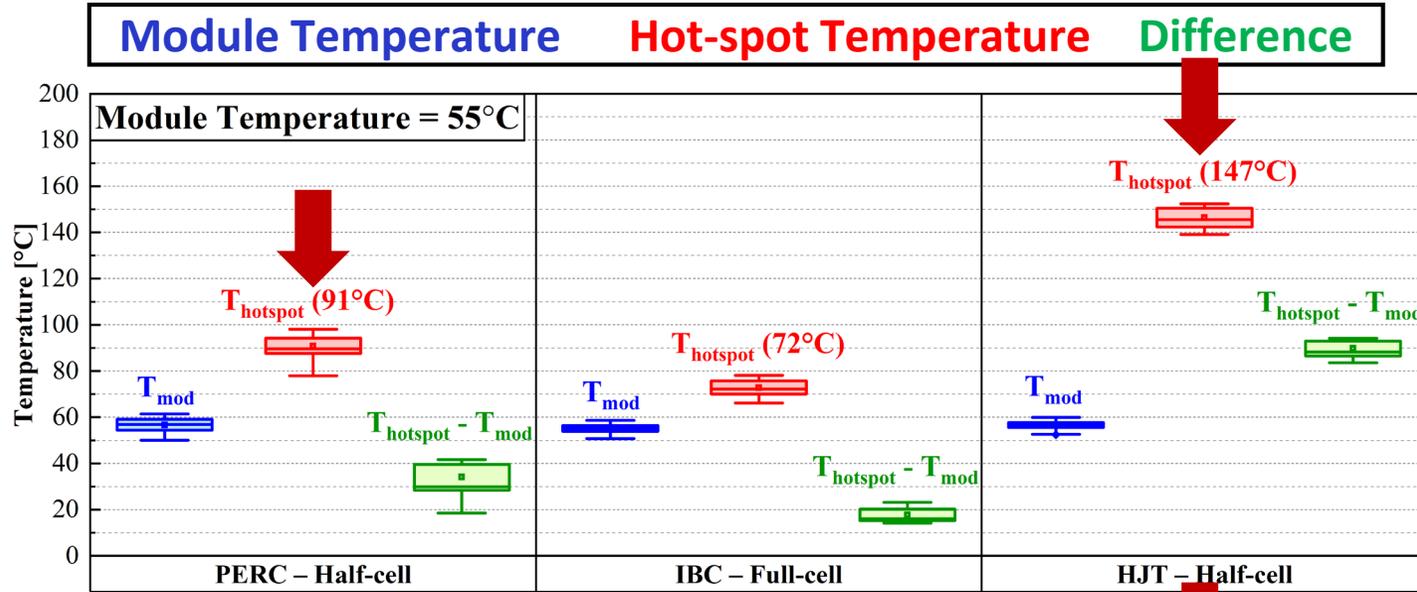


**Step 3: Light soaking**



- Short-circuit condition
- $1000 \pm 100 \text{ W/m}^2$
- $55 \pm 15^\circ\text{C}$  module temp.
- 1 hour + 4 hours

# Module and Hot-Spot Temperatures during HS Tests

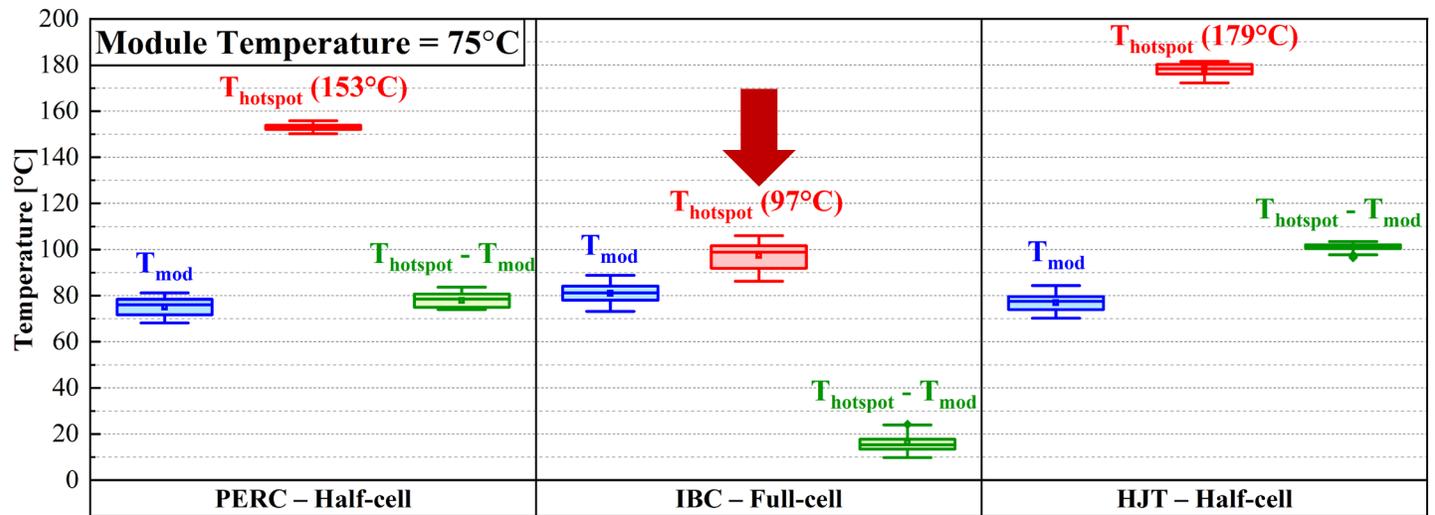
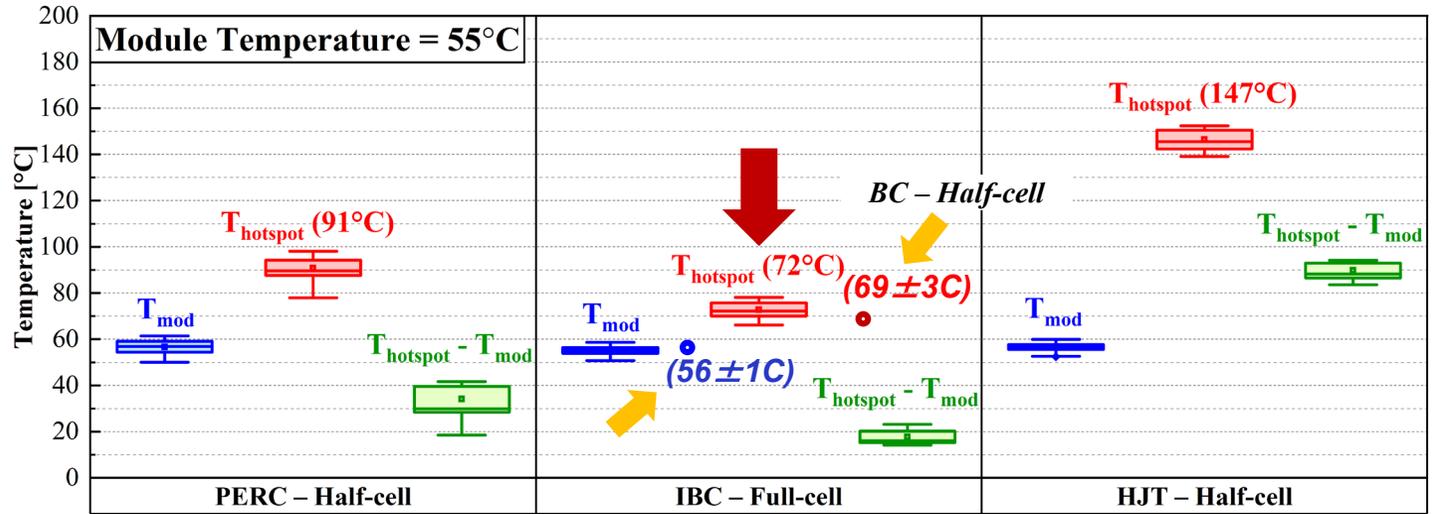


C. Reichel et al., Sol. En. Mat. (2022)

- **HJT and PERC – Half-cell modules have the highest hot-spot temperature**
- IBC module has the lowest hot-spot temperature
- Shorter string, lower hot-spot temperature (less negative reverse voltage) – PERC

# Module and Hot-Spot Temperatures during HS Tests

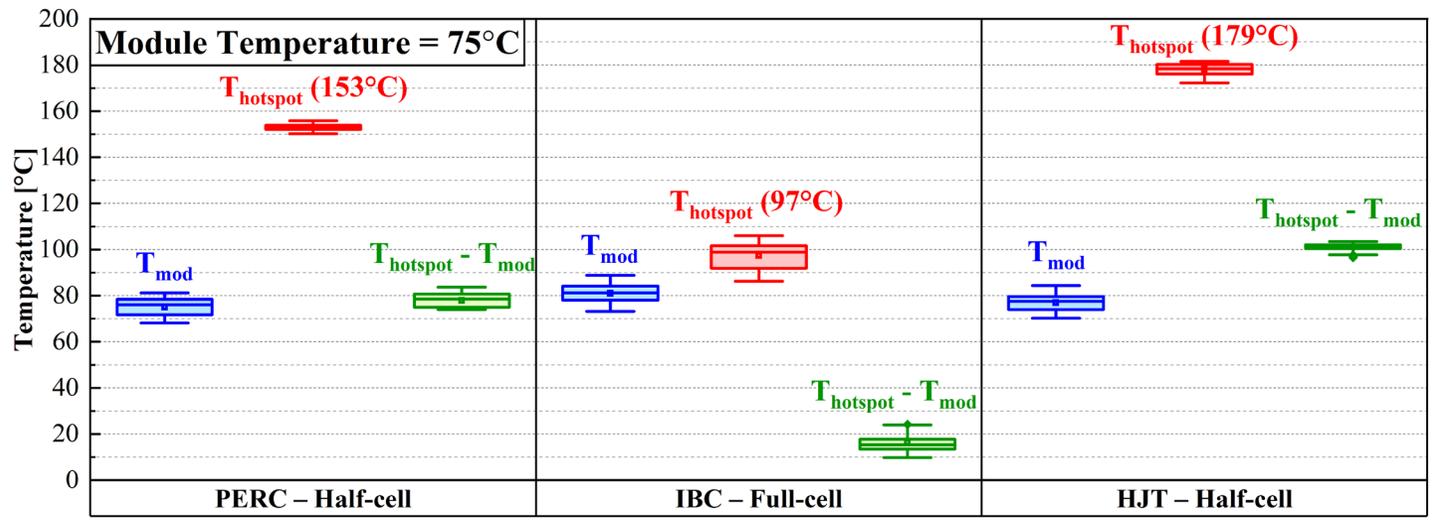
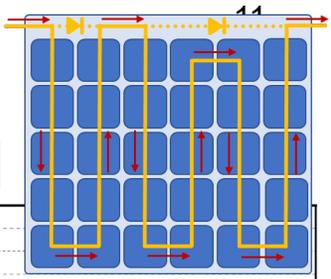
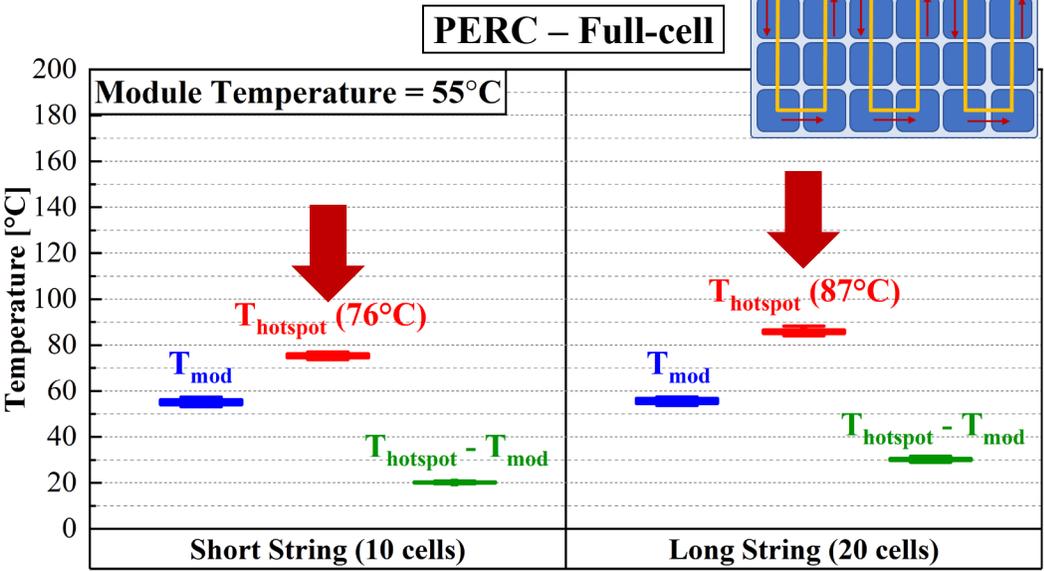
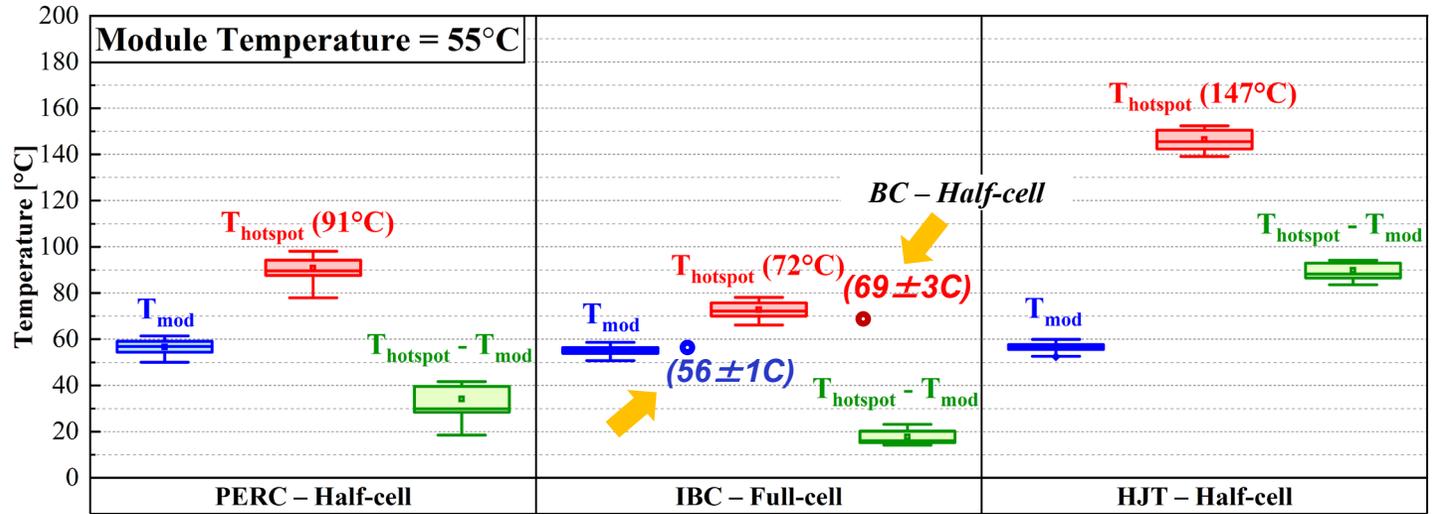
**Module Temperature**    **Hot-spot Temperature**    **Difference**



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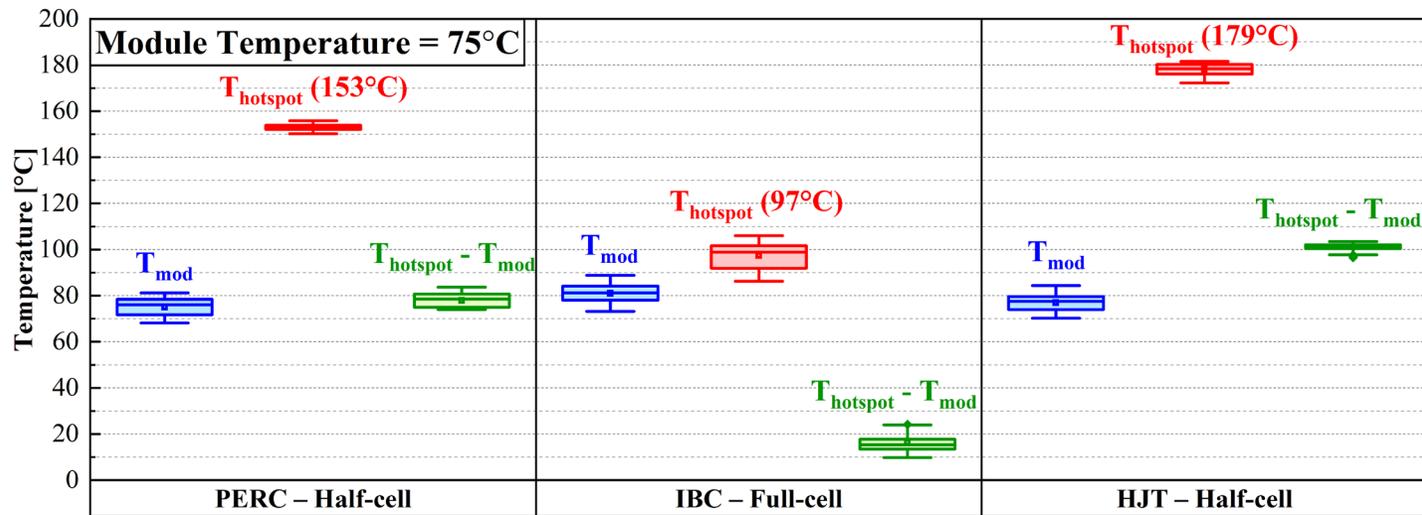
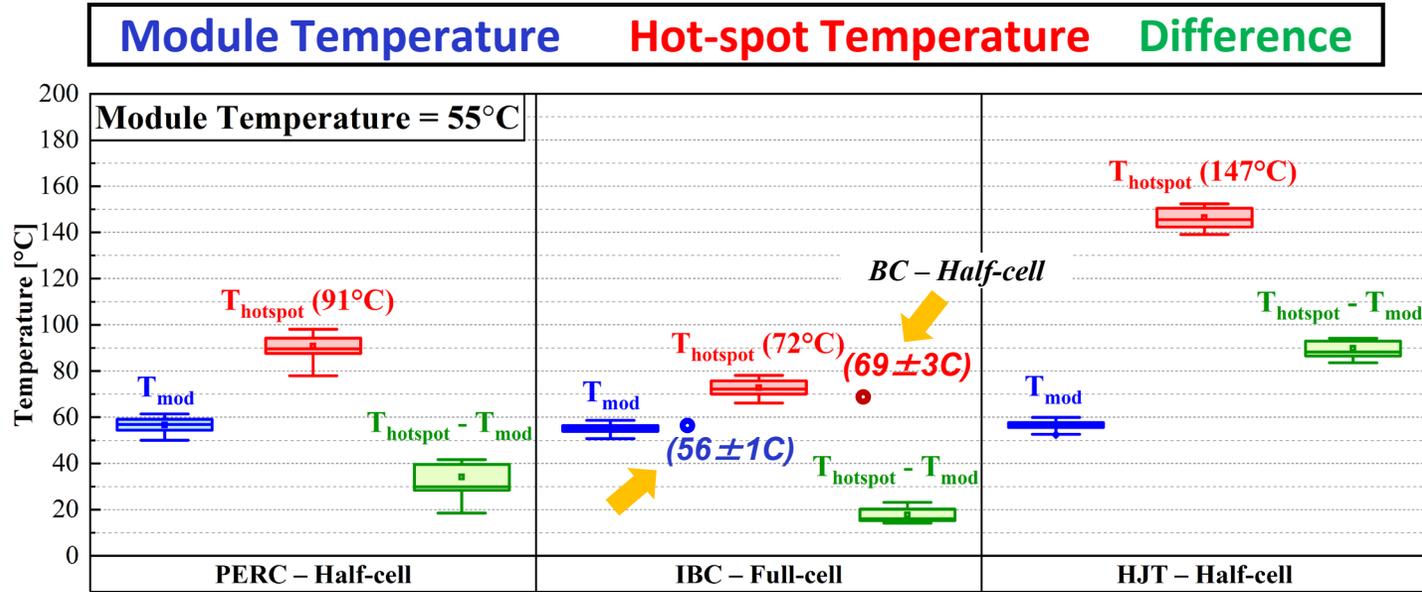
# Module and Hot-Spot Temperatures during HS Tests

**Module Temperature**    **Hot-spot Temperature**    **Difference**



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# Module and Hot-Spot Temperatures during HS Tests



## What temperatures are dangerous?

- IEC 61730-2 MST 21 Temperature Test exposes the module to 1000 W/m<sup>2</sup> sunlight until the temperature stabilized, and the pass criteria is that **no measured temperature exceed the limits of the surface materials (e.g. TI/RTE/RTI)**, as TI/RTE/RTI is the maximum service temperature at which the critical properties of a material will remain within acceptable limits over a long period of time.

10.15.4 Pass criteria

The pass criteria are as follows:

- No measured temperatures exceed any of the applicable temperature limits (e.g. TI/RTE/RTI) of surfaces, materials, or components. Thermal material requirements are given in 5.5 of IEC 61730-1:2016.
- No visual defects as defined in MST 01.
- MST 16, MST 17 shall meet the same requirements as for the initial measurements.

IEC 61730-1 requires reporting of the maximum measured operating temperature as determined by this test method.

- RTI (relative temperature index):** characteristic parameter related to the ability of plastic materials to resist thermal degradation.
- RTE:** Relative Thermal Endurance
- TI:** Thermal Index

3.5.5.3

relative temperature index

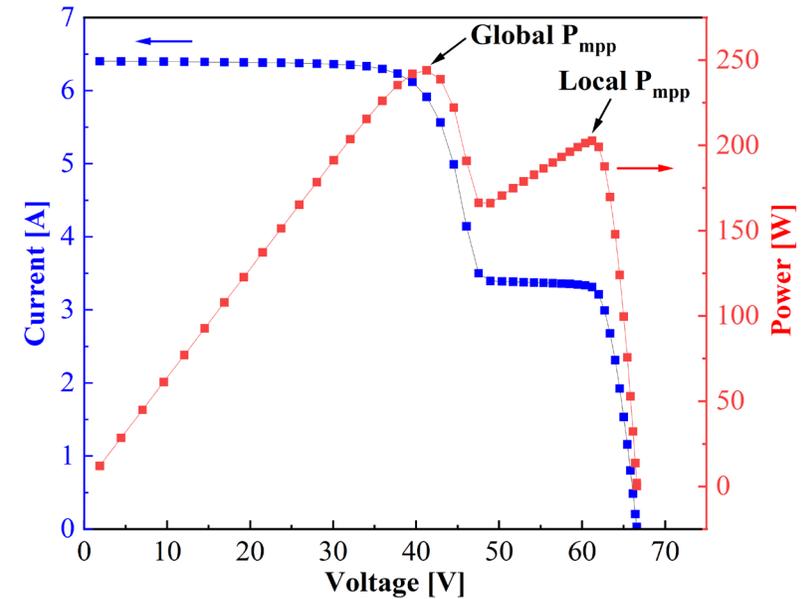
RTI

temperature index of an insulating material or system obtained from the time which corresponds to the known temperature index of a reference material or system when both are subjected to the same ageing and diagnostic procedures in a comparative test

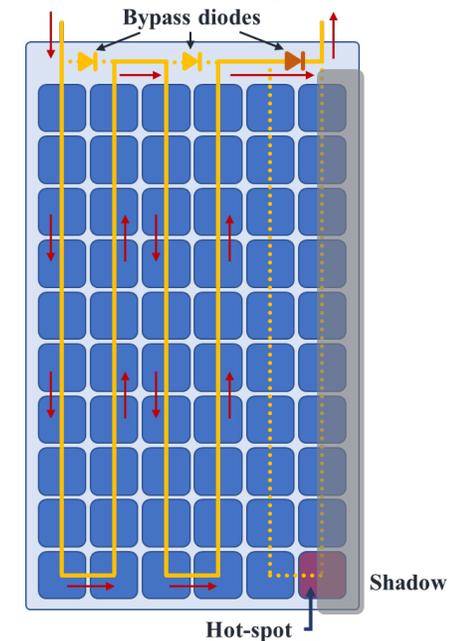
[SOURCE: IEC 60050-212:2010, 212-12-12]

# Outdoor Accelerated Ageing Test using Shadow Masks

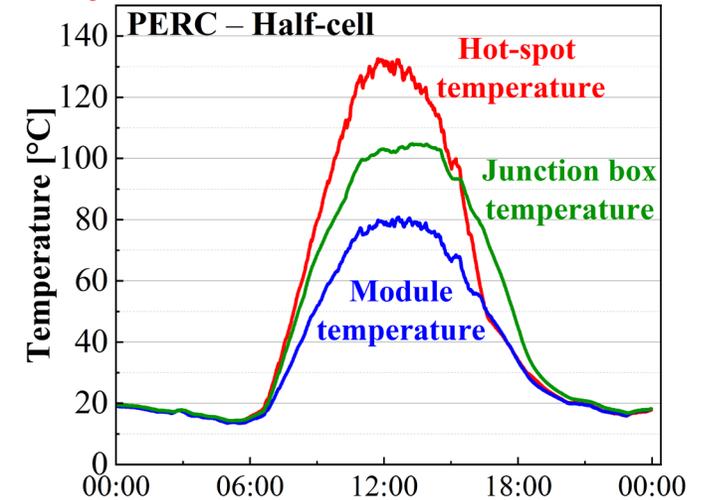
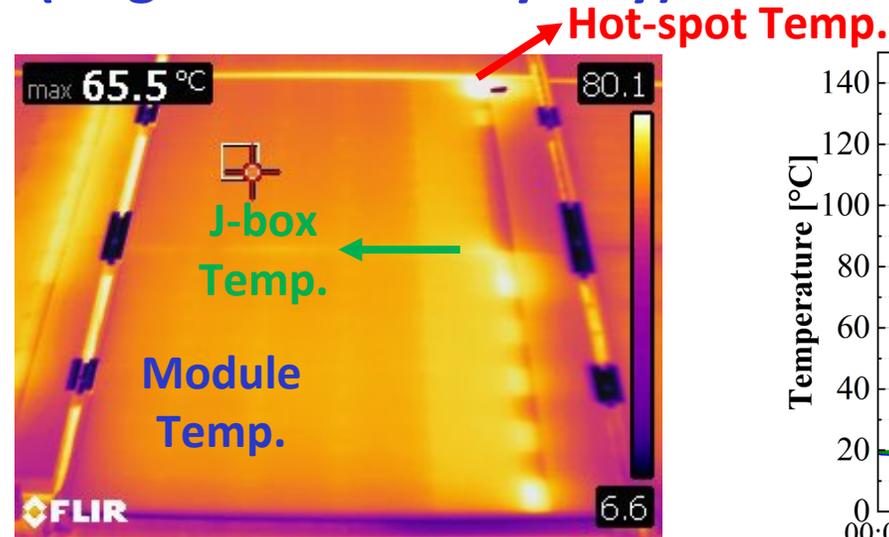
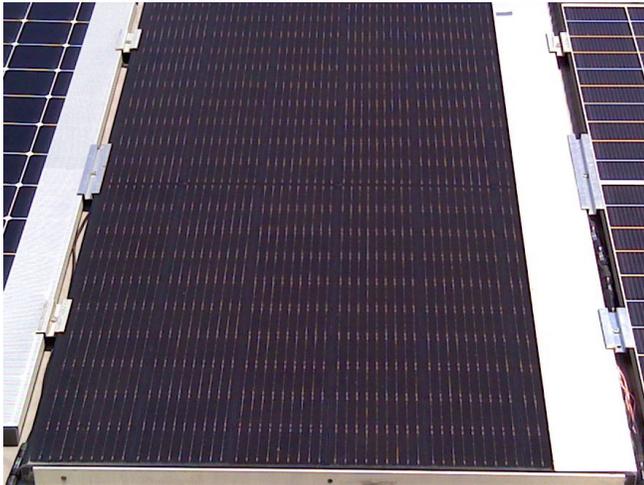
## Outdoor Accelerated Ageing using Shadow Masks



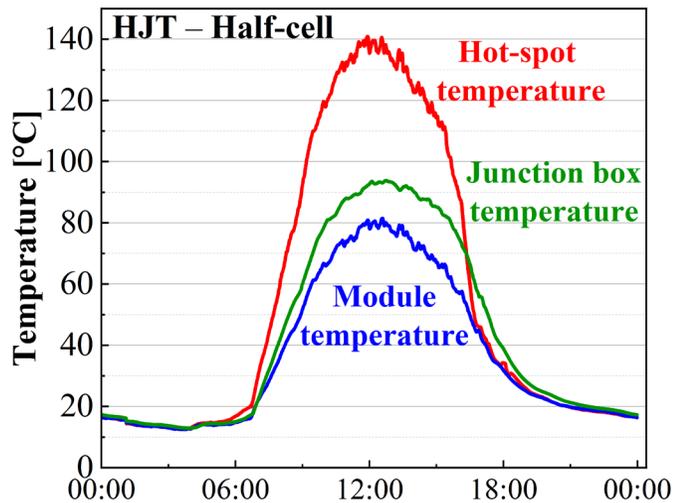
- Stress on **bypass diode** and **module materials**
- Difference between **Global  $P_{mpp}$**  and **Local  $P_{mpp}$**  is  $10 \pm 5\%$
- Shadow mask **36% transmittance**
- 13 months of monitoring
- **Module, hot-spot** and **junction box temperatures** every minute
- IV curves every minute



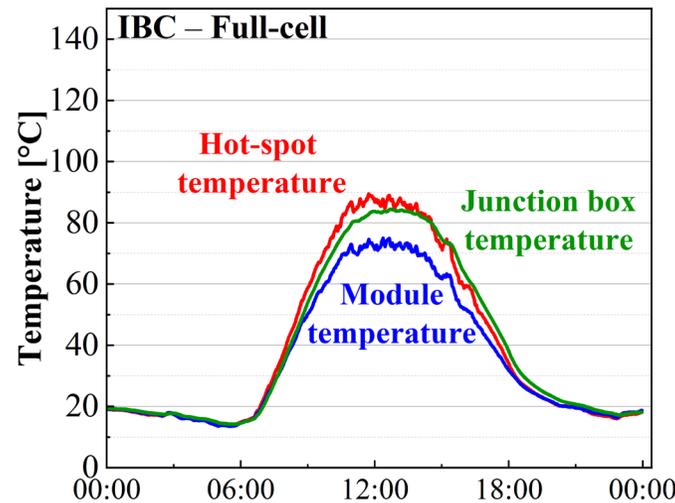
# Daily Temperature Profiles (August – Clear Sky Day)



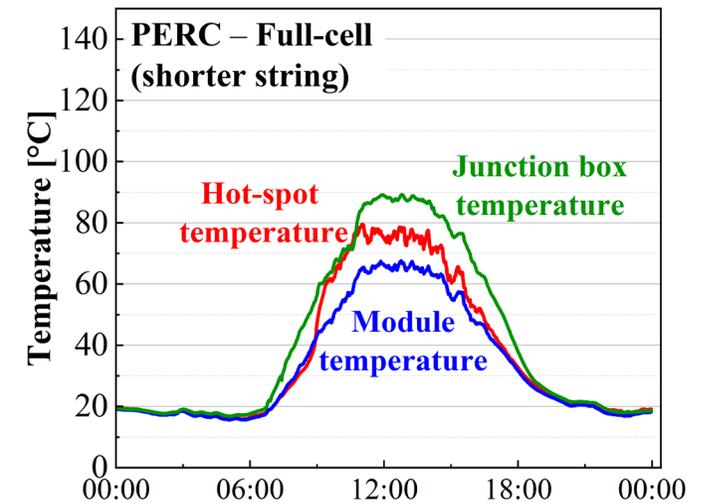
**BIPV-Insulated (no ventilation)**



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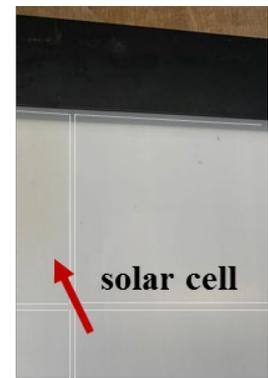
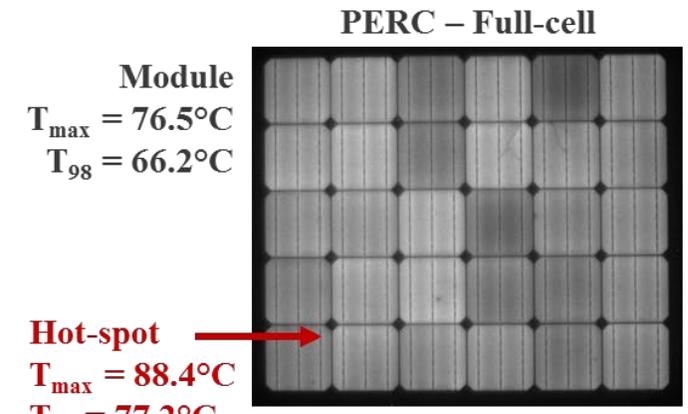
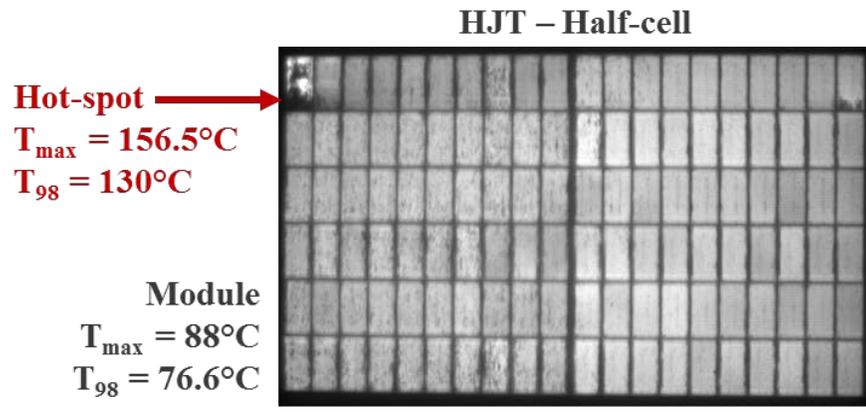
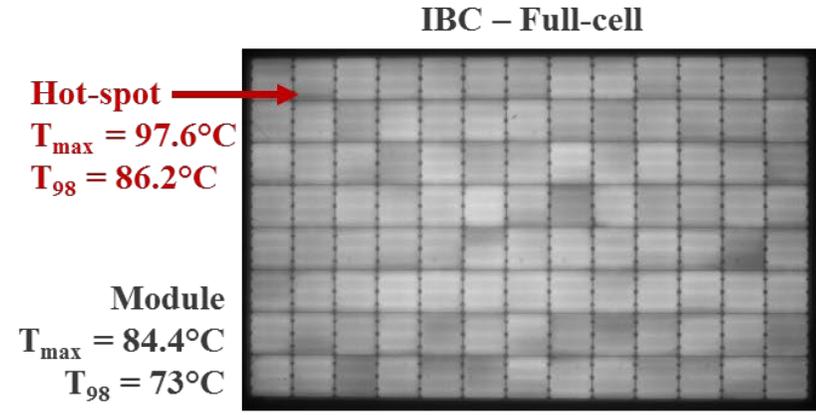
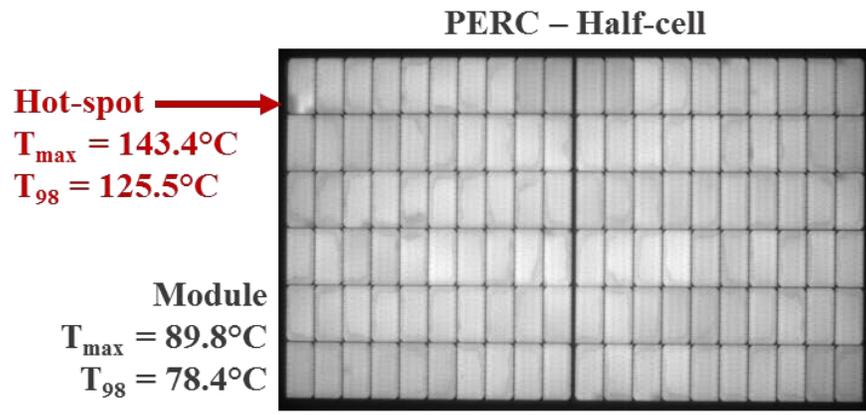


**BIPV-Insulated (no ventilation)**



**BIPV-Partially Ventilated**

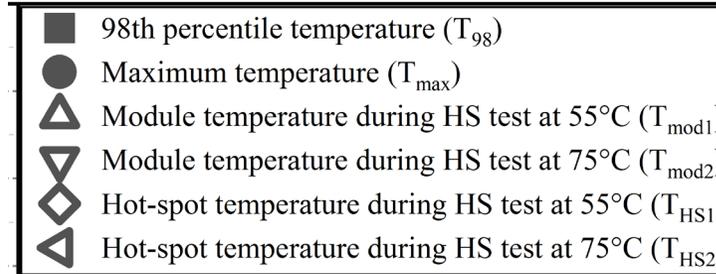
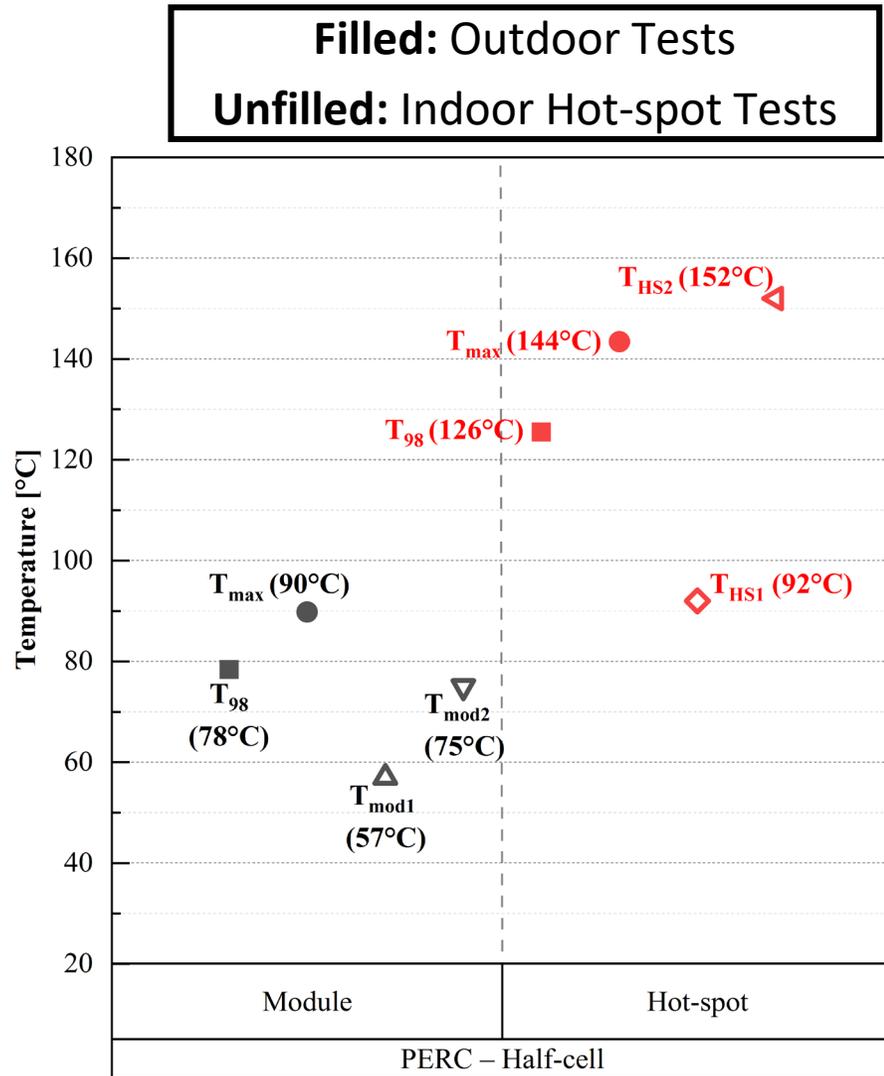
# Performance Change After 13 Months



- There are changes in the performance of unshaded and shaded modules, but there is **no performance change attributable to the shadow mask.** (*update: after 2 years, shaded HJT degraded more than unshaded HJT*)<sup>[1]</sup>
- **No diode failure** after slightly more than 2 years of monitoring
- **PERC – Half-cell** and **HJT – Half-cell** modules → Darker areas - Shunt faults?
- **PERC – Half-cell** → **Discoloration of encapsulant and backsheet**

[1] G. Friesen, et al. EUPVSEC (2024)

# Sufficiency of Hot-Spot Test for BIPV Testing

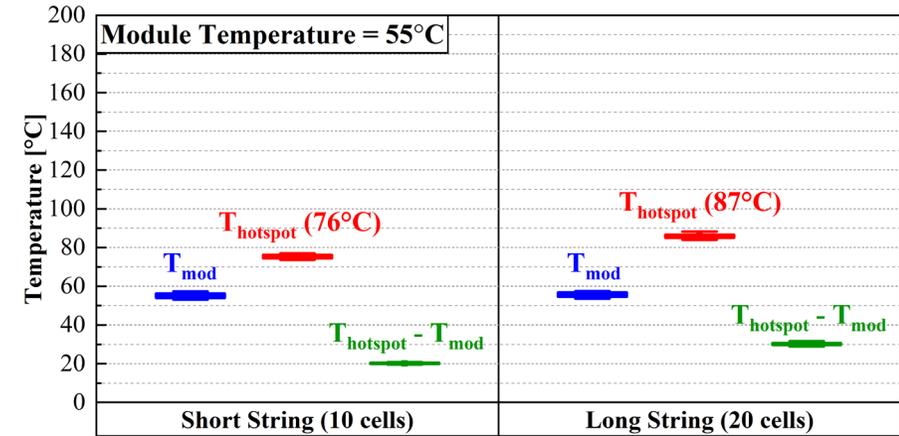
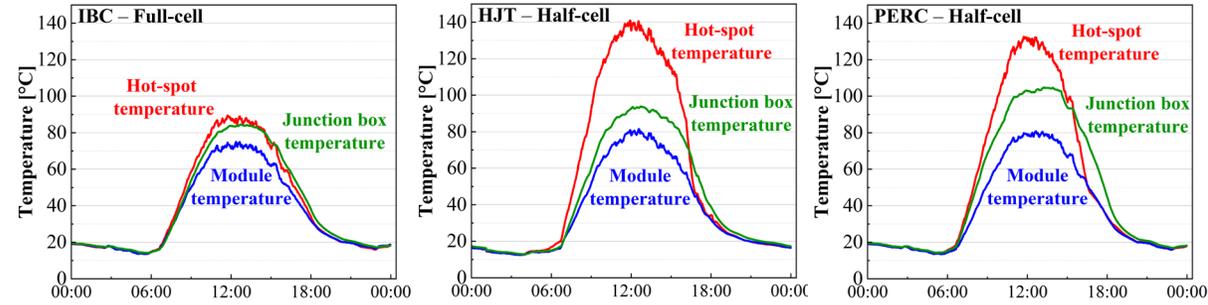


Hot-spot Endurance Test	IEC 61215-2:2021 (2016)	Level 1 (70°C < $T_{98} \leq 80^\circ\text{C}$ )	Level 2 (80°C < $T_{98} \leq 90^\circ\text{C}$ )
IEC TS 63126:2020	55±15°C (50±10°C)	60±10°C	70±10°C
Proposal of this study	55±15°C	75±15°C	85±15°C

**HS test should be performed at higher module temperatures for BIPV testing!**

# Summary and Conclusions

- Effect of **cell technology** on hot-spot temperature
  - Reverse characteristics ( $V_{br}$ , bypass diode function)
  - **BC-Full-cell** and **BC-Half-cell modules** have similar hot spot temperatures
- Effect of **string length** on hot-spot temperature
  - Shorter string  $\rightarrow$  less negative reverse voltage, less heating for PERC
  - **BC modules?**
- **Sufficiency of HS test for BIPV** in terms of testing temperature
  - 15° C higher module temperature for Level 1 & 2 in IEC TS 63126:2020



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# Thank you for your attention!

## Acknowledgement:

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